WMSC040F12B1L-B

N-Channel Silicon Carbide MOSFET Module

Rev.03 - 29 October 2025

Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and Integrated NTC temperature sensor, configured with Pressfit pin and pre-applied thermal paste.



2. Features and benefits

- H Bridge topology
- Press-fit pin type
- · Pre-applied thermal interface material
- Low Switching Losses
- Low Q_g and C_{rss}
- Low Inductive Design
- Low R_{DSon}

3. Applications

- Power inverters
- AC-DC converters
- · Active power factor correctors
- · Motor drives

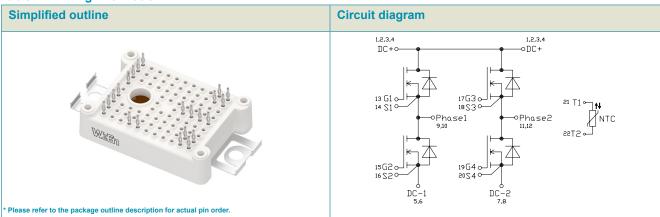
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values Values			Unit
Absolute	maximum rating						
V _{DS}	drain-source voltage	T _j = 25 °C		1200			V
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			47		Α
P _{tot}	total power dissipation	T _h = 25 °C			114		W
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
R _{DS(on)}	drain-source on-state resistance	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	115	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	17.5	-	nC
Source-d	rain diode		J		'		
Q _r	recovered charge	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt = 3400 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_{i} = 25 °C		-	465	-	nC

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	•	Package issue date
WMSC040F12B1L-B	WeEnPACK-B1	WMSC040F12B1L-B6T	Tray	24	WeEnPACK- B1PFB-B	20-Mar-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040F12B1L-B	WMSC040F12B1L-B

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Notes	Values	Unit
storage temperature			-40 to 125	°C
operating junction temperature			-40 to 150	°C
maximum junction temperature	Intermittent condition with shortened lifetime		-40 to 175	°C
RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
drain-source voltage	T _j = 25 °C		1200	V
gate-source voltage	Absolute maximum values		-12 to 24	V
gate-source voltage	Recommended operational values		-4 to 18	V
total power dissipation	T _h = 25 °C		114	W
drain current	V _{GS} = 18 V; T _h = 25 °C		47	Α
	V _{GS} = 18 V; T _h = 100 °C		30	Α
peak drain current	pulse width tp limited by T_{jmax}		100	А
single pulse drain-to- source avalanche	I_{AS} = 24 A; L = 1 mH; V_{DD} = 100 V; $T_{j(init)}$ = 25 °C; per MOSFET		288	mJ
e				
DC body diode forward current	$T_h = 25 ^{\circ}C; V_{GS} = -4 V$		30	Α
Pulse body diode current	verified by design, tp limited by T_{jmax}		100	Α
	storage temperature operating junction temperature maximum junction temperature RMS isolation voltage drain-source voltage gate-source voltage gate-source voltage total power dissipation drain current peak drain current single pulse drain-to-source avalanche DC body diode forward current		storage temperature operating junction temperature maximum junction temperature lifetime lifetime lifetime lifetime $T_j = 25 ^{\circ}\text{C}$; all terminals shorted; $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 50 \text{Hz}$; $t = 1 \text{s}$ $f = 100 \text$	storage temperature

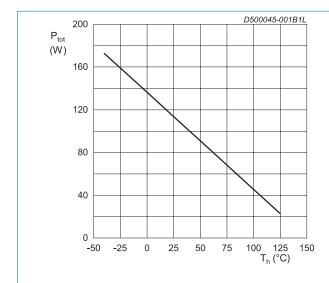


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

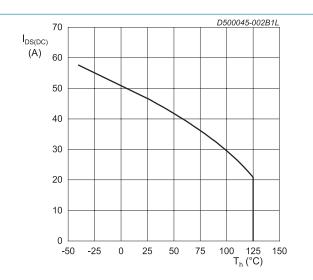


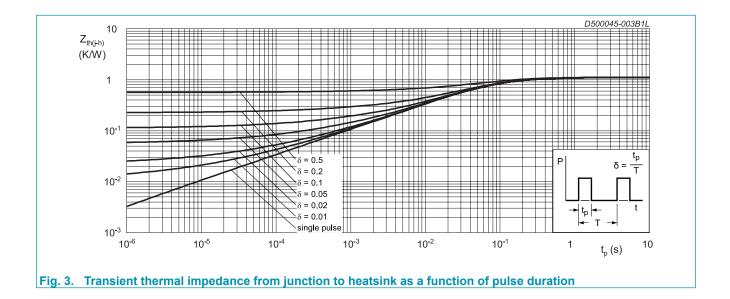
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{\text{th(j-c)}}$	thermal resistance from junction to case	per MOSFET		-	0.75	-	K/W
$R_{\text{th(j-h)}}$	thermal resistance from junction to heatsink	per MOSFET, valid with pre-applied thermal interface material, λ_{grease} = 4 W/(m·K), thick _{grease} = 50 um		-	1.1	-	K/W
Internal Isolation		basic insulation (class 1, IEC 61140)		Al_2O_3			
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
CTI	Comperative tracking index			>200		,	
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommended.

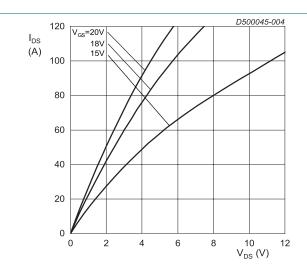


10. Characteristics

Table 7. Characteristics

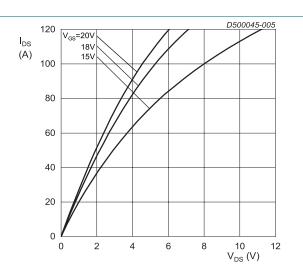
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
	aracteristics		1		-71		
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 100 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}\text{C}$		1200	-	-	V
$V_{GS(th)}$	gate-source threshold	$I_D = 10 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$		1.9	2.6	3.5	V
	voltage	I _D = 10 mA; V _{DS} = V _{GS} ; T _j = 175 °C		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.2	100	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 125 °C		-	46	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 150 °C		-	51	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 175 °C		-	54	-	mΩ
R_G	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	1	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 33 A; T _j = 25 °C		-	20	-	S
Dynamic	characteristics		,				
Q _{G(tot)}	total gate charge	I _D = 33 A; V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	115	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	47	-	nC
Q_{GD}	gate-drain charge			-	17.5	-	nC
C _{iss}	input capacitance	$V_{DS} = 1000 \text{ V}; V_{GS} = 0 \text{ V}; f = 100 \text{ KHz};$		-	2.45	-	nF
C _{oss}	output capacitance	$T_j = 25 ^{\circ}\text{C}$		-	108	-	pF
C _{rss}	reverse transfer capacitance			-	11	-	pF
E _{oss}	Coss stored energy			-	54	-	μJ
$t_{d(on)}$	turn-on delay time	$V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	27	-	ns
t _r	rise time	$R_{G(ext)} = 5.1 \Omega$; $I_D = 33 A$; $L = 300 \mu H$; $I_j = 25 °C$		-	30	-	ns
$t_{d(off)}$	turn-off delay time	, i		-	42	-	ns
t _f	fall time			-	11	-	ns
E _{on}	turn-on energy			-	612	-	μJ
E _{off}	turn-off energy	1		-	90	_	μJ

Body dic	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,				
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_{SD} = 33 \text{ A}; T_j = 25 \text{ °C}$		-	5.5	-	V
		V_{GS} = -4 V; I_{SD} = 33 A; T_{j} = 150 °C		-	5.0	-	V
Dynamic	characteristics					•	
I _{rrm}	reverse recovery current	$I_{SD} = 33 \text{ A}; V_{GS} = -4 \text{ V}/18 \text{ V}; V_{R} = 600 \text{ V};$		-	44	-	Α
t _{rr}	reverse recovery time	di/dt = 3400 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	19	-	ns
Q _r	recovered charge	1		-	465	-	nC
E _{rec}	reverse recovery energy			-	117	-	μJ
NTC ther	mistor		'				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C			465±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	S



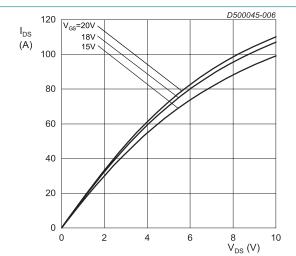
 $T_j = -40 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values



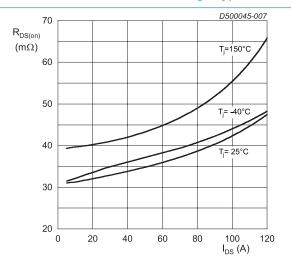
 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values

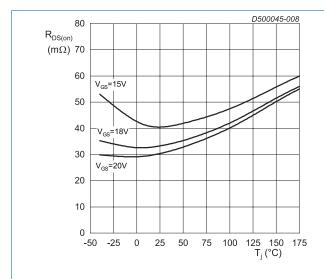


 $T_i = 150 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

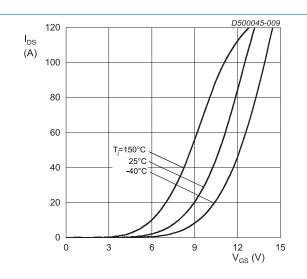


 $V_{GS} = 18 \ V; \ t_p < 200 \ \mu s$ Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



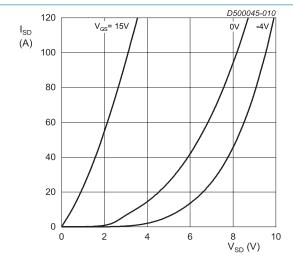
 I_{DS} = 33 A; t_p < 200 μ s

Fig. 8. Drain-source on-state resistance as a function of junction temperature



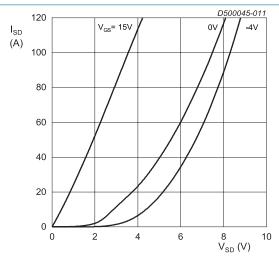
 $V_{DS} = 20 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



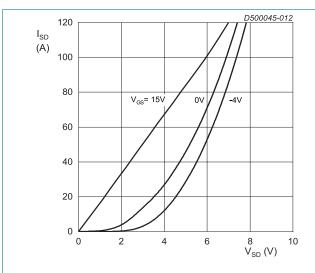
 $T_j = -40 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

Fig. 10. Body diode forward characteristics; typical values

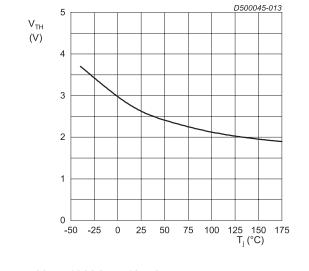


 $T_i = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

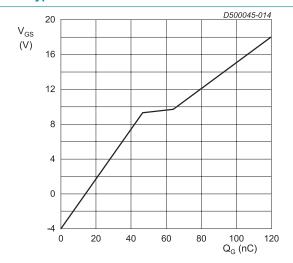
Fig. 11. Body diode forward characteristics; typical values



T_j = 150 °C; t_p < 200 μs Fig. 12. Body diode forward characteristics; typical values



V_{DS} = 10 V; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature



 I_{DS} = 33 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

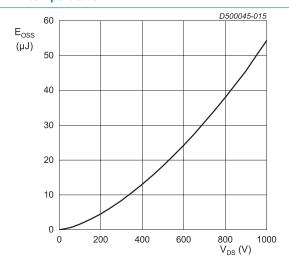
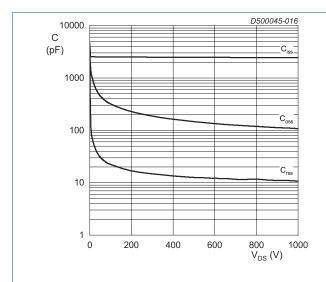
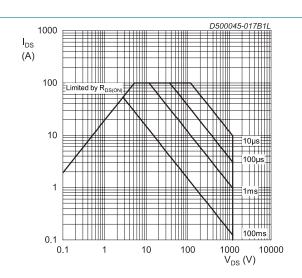


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



 $V_{DS} = 0 - 1000 \text{ V}$

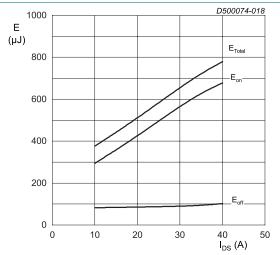
 $T_j = 25 \text{ °C}; V_{AC} = 25 \text{ mV}; f = 100 \text{ KHz}$



 T_h = 25 °C; D = 0 Parameter: t_p

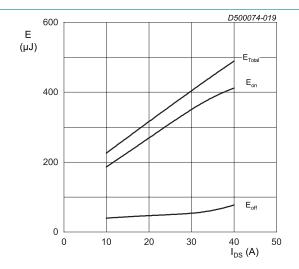
Fig. 17. Forward bias safe operating area





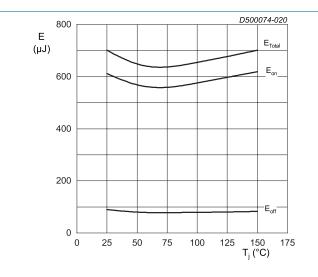
 T_j = 25 °C; V_{DD} = 800 V; $R_{G(ext)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



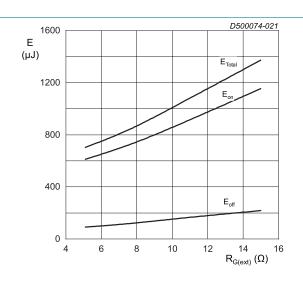
 T_j = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



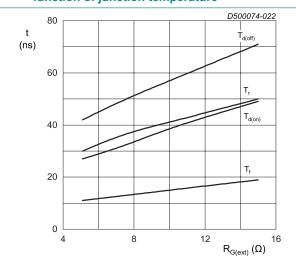
 $I_{DS}=33$ A; $V_{DD}=800$ V; $R_{G(off)}=5.1$ $\Omega;$ $R_{G(on)}=5.1$ $\Omega;$ $V_{GS}=$ -4 V/18 V; $L=300~\mu H$

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 300 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 33 A; $V_{\rm GS}$ = -4 V/18 V; L = 300 μH

Fig. 22. Switching time as a function of external gate resistance

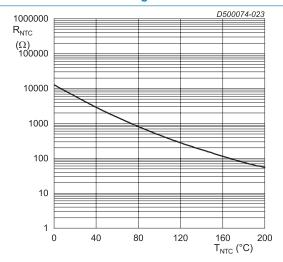
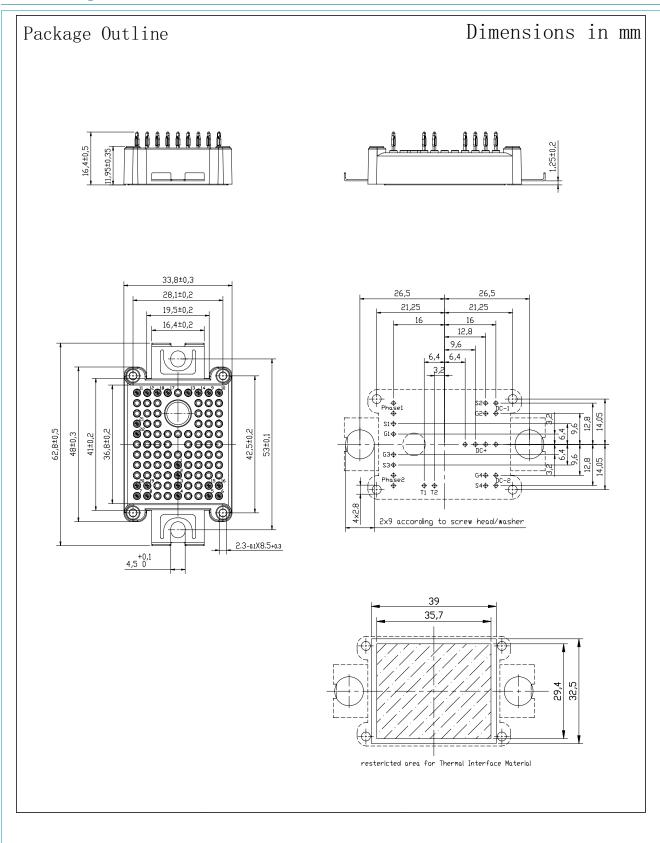


Fig. 23. NTC thermistor resistance as a function of NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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WMSC040F12B1L-B

N-Channel Silicon Carbide MOSFET Module

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Product data sheet

13. Contents

1. General description	1
2. Features and benefits	1
3. Applications	1
4. Quick reference data	1
5. Pinning information	2
6. Ordering information	2
7. Marking	2
8. Limiting values	3
9. Thermal & Mechanical characteristics	4
10. Characteristics	5
11. Package outline	12
12. Legal information	13
13. Contents	15

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